

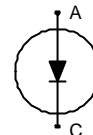
## Silicon Carbide Schottky Diode

### FEATURES:

- Revolutionary semiconductor material - Silicon Carbide
- Switching behavior benchmark
- No reverse recovery
- No temperature influence on the switching behavior
- No forward recovery

### Applications:

- SMPS, PFC, snubber



Chip Type	V <sub>BR</sub>	I <sub>F</sub>	Die Size	Package	Ordering Code
SIDC24D60SIC3	600V	8A	1.706 x 1.38 mm <sup>2</sup>	sawn on foil	Q67050-A4281-A101

### MECHANICAL PARAMETER:

Raster size	1.706x 1.38	mm
Anode pad size	1.405 x 1.08	
Area total / active	2.354 / 1.548	mm <sup>2</sup>
Thickness	355	µm
Wafer size	75	mm
Flat position	0	deg
Max. possible chips per wafer	1649 pcs	
Passivation frontside	Photoimide	
Anode metalization	3200 nm Al	
Cathode metalization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding	
Die bond	Electrically conductive glue or solder	
Wire bond	Al, ≤ 350µm	
Reject Ink Dot Size	Ø ≥ 0.3 mm	
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C	

## Maximum Ratings

Parameter	Symbol	Condition	Value	Unit
Repetitive peak reverse voltage	$V_{RRM}$		600	V
Surge peak reverse voltage	$V_{RSM}$		600	
Continuous forward current limited by $T_{jmax}$	$I_F$		8	A
Single pulse forward current (depending on wire bond configuration)	$I_{FSM}$	$T_C = 25^\circ C, t_P = 10 \text{ ms sinusoidal}$	26	
Maximum repetitive forward current limited by $T_{jmax}$	$I_{FRM}$	$T_C = 100^\circ C, T_j = 150^\circ C, D = 0.1$	32	
Non repetitive peak forward current	$I_{FMAX}$	$T_C = 25^\circ C, t_P = 10 \mu s$	80	
Operating junction and storage temperature	$T_j, T_{stg}$		-55...+175	$^\circ C$

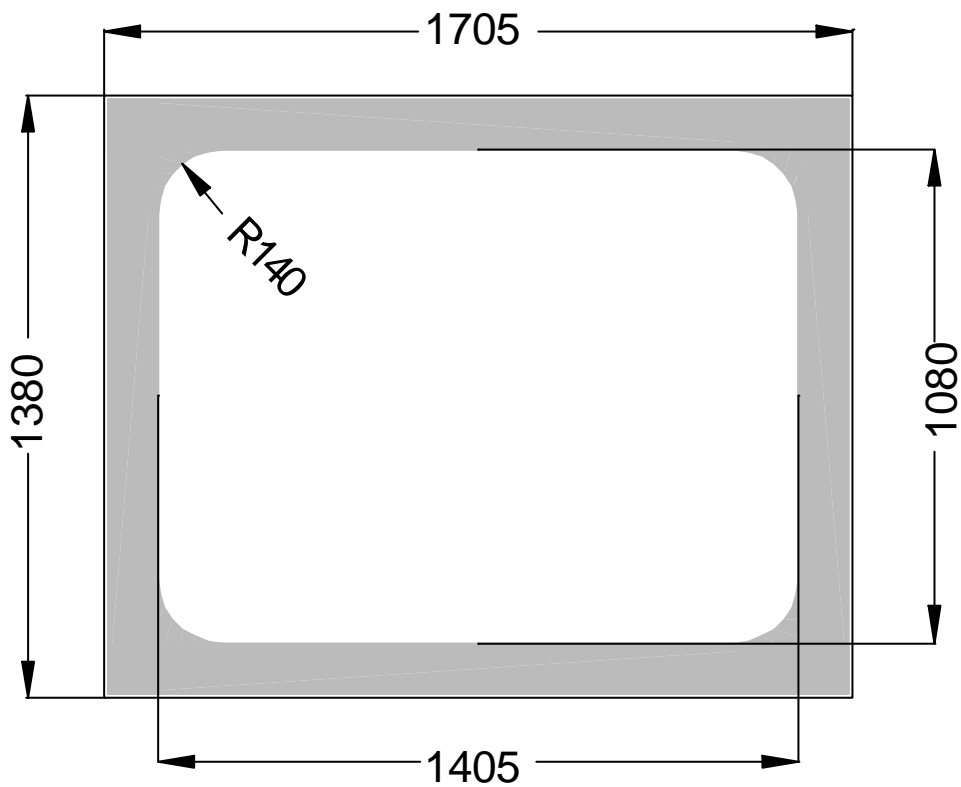
## Static Electrical Characteristics (tested on chip), $T_j = 25^\circ C$ , unless otherwise specified

Parameter	Symbol	Conditions		Value			Unit
				min.	Typ.	max.	
Reverse leakage current	$I_R$	$V_R = 600V$	$T_j = 25^\circ C$		28	300	$\mu A$
Forward voltage drop	$V_F$	$I_F = 8A$	$T_j = 25^\circ C$		1.5	1.7	V

## Dynamic Electrical Characteristics, at $T_j = 25^\circ C$ , unless otherwise specified, tested at component

Parameter	Symbol	Conditions		Value			Unit
				min.	Typ.	max.	
Total capacitive charge	$Q_C$	$I_F = 8A$ $di/dt = 400A/ms$ $V_R = 200V$	$T_j = 150^\circ C$		24		nC
Switching time	$t_{rr}$	$I_F = 8A$ $di/dt = 400A/ms$ $V_R = 200V$	$T_j = 150^\circ C$		n.a.		ns
Total capacitance	C	$I_F = 8A$ $di/dt = 400A/ms$ $T_j = 25^\circ C$ $f = 1MHz$	$V_R = 1V$		280		pF
			$V_R = 150V$		26		
			$V_R = 300V$		18		

CHIP DRAWING:



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**FURTHER ELECTRICAL CHARACTERISTICS:**

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This chip data sheet refers to the device data sheet

INFINEON TECHNOLOGIES

SDT08S60

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**Description:**

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AQL 0,65 for visual inspection according to failure catalog

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Electrostatic Discharge Sensitive Device according to MIL-STD 883

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Test-Normen Villach/Prüffeld

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